

High Impedance Fault Detection In Radial Feeder Under Different Micro Climatic Conditions Using Optimised Support Vector Machine Algorithms

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Abstract

Detection of high impedance faults (HIF) in radial feeders is a challenging task. HIF faults occurs mostly due to single line to ground faults in rural and semi urban areas in Andhra Pradesh, India of about 80%. Existing methods detect the single line to ground faults (SLGF) and not classifies the subtypes of SLGF faults such as small-impedance faults (SIFs), medium-impedance faults (MIFs), high-impedance faults (HIFs), arc grounding faults (AGFs), intermittent grounding faults (IGFs), and transient grounding faults (TGFs). SLGF subtype classification helps for selective tripping, Minimizes Outages, Limits Prolonged Fault Operation, Prevents Cascading Failures and improves the system monitoring. In this paper, optimized Support Vector Machines (SVM) algorithms such as (i)cubic-SVM, (ii) PSO-SVM and (iii) BO-SVM are proposed for the detection and classification of the HIF under different environmental i.e. microclimatic conditions. From the results, BO-SVM provides the better accuracy of 97% in HIF detection and subtype classification for 4 - node and 13 -node IEEE radial test feeders. The proposed algorithms are compared with the traditional algorithms and evaluated the performance analysis.

Keywords Evaluation metrics, High Impedance Fault, Linear Regression, Support Vector Machines, microclimatic conditions.

INTRODUCTION

In radial feeder distribution system, the energized conductor contacts the ground surface and leads to high impedance fault (HIF). HIF cause life threatening for living beings due to transfer of power in and around the fault premises. Above 80 percent of the faults are occurring due to single line to ground (L-G) fault. When the energized conductor falls on the surfaces such as asphalt, sand, grass etc. starts conducting through them and surfaces have low impedance value. This low impedance leads to small current, which is equivalent to load current value and could never be detected through conventional protection systems such as over current relays.

In [1], HIF fault locations are detected using SVM algorithm for dc microgrids. In [2], HIF detection and isolation method in power distribution network were performed through Principal Component Analysis (PCA), Fisher Discriminant Analysis, Binary and Multiclass SVM. Multiclass SVM provides high accuracy than traditional methods and ensures reliability, security, and dependability of distribution network. In [3], identified and categorized the LL and LG faults on the DC side of PV systems. The authors used hierarchical method to decrease the training dataset for the learning process, and applied the machine learning algorithms. The hierarchical method had achieved an accuracy of about 96.66% and 91.66%. In [4], single ended travelling wave-based fault location method for a hybrid transmission line was developed. Discrete Wavelet Transform (DWT) is used for the transient extraction and SVM is used for the fault identification. The developed method is used for different fault identifications such as different Fault Inception Angles (FIA), fault resistances, Non-Linear High Impedance Faults (NLHIF). In [5], HIFs is classified in the distribution systems. Hermite Transform (HT) is used and compared with DWT, improved performance the of HIFs detection. In [6], HIF detection system based on Kernel Extreme Learning Machine (KELM) has been used for the detection of HIFs. DWT and Hilbert-Huang Transform

(HHT) are used to characterize the HIF. XG Boost-based fault feature selection is utilized for characterization of HIFs. The KELM provides high accuracy in HIF detection.

In [7], HIF detection is performed based on incremental learning for non-stationary data streams with changing distributions. The Stationary Wavelet Transform (SWT) is extracts the fault characteristics, Back Propagation Neural Network (BPNN) is utilized for HIF detection. The suggested approach maintains a high degree of detection accuracy for current cycle data and improves the reliability in HIF detection. In [8], power system analysis tool pandapower is used for the fault detection using time series calculations. In [9], radial test feeders are utilized for fault detection. In [10], Multi Resolution Analysis (MRA) and Adaptive Neuro Fuzzy Inference System (ANFIS) are used for the discrimination of HIF such as load switching and capacitor switching. The proposed method has high reliability in differentiating HIF during different transient conditions.

In [11], authors developed differential protection of distribution line of 5-bus system, which contain a wind farm in the microgrid for HIF detection through different machine learning algorithms such as Decision Tree (DT), Random Forest (RF), Gradient Boost (GB), Multilayer perceptron, Naïve Bayes (NB), K-Nearest Neighbor (KNN), and SVM. SVM is used for the purpose of maintaining the security and dependability of microgrid protection. In [12], authors analysed the status of distribution networks using supervised learning algorithms such as Feed Forward Neural Network (FFNN), LR, and SVM for IEEE 34 and 37 node test feeders. The impact of errors in measurement studied using FFNN and SVM algorithms. In [13], HIF detection in solar PhotoVoltaic (PV) integrated power system was performed using recurrent neural network-based Long Short-Term Memory (LSTM) in IEEE 13 bus system, which was interconnected with 300 KW solar PV plants. DWT was applied for feature extraction and compared with KNN, SVM, J48 DT and NB algorithms. LSTM outperforms all the performance indices (PI) compared to the other techniques. In [14], deployed a HIF model and the combination of DWT and SVM was presented for HIF detection. An Eskom network was utilized for this study. In [15], ML based algorithm was used for the detection of arc fault in experimental testbed. Udo0 X86 ultra microcontroller was utilized for implementing the proposed method and the results were tested in distribution system. In [16], discrete wavelet packet transform (DWPT) and machine learning were used for identification of feeder Malfunction. In [17], conventional autoencoder framework for HIF detection (CAE-HIFD) was used in IEEE 13-node feeder for HIF detection. In [18], pattern recognition method was used for the detection of High Impedance Arcing Faults (HIAFs). Training data were extraction from 25KV microgrid, which includes of distributed generation (DG) and renewable energy sources. The developed methodology was compared with the Pearson Correlation Coefficient (PCC) and PCA method for rapid identification of HIAF in a microgrid.

In [19], automatic detection and diagnosis algorithm framework using three different ML classifiers such as DT based on different split criteria, K-NN based on different distance and weighting functions, SVM based on different kernel functions and multi classifier approaches, and Bayesian optimization are applied to tune hyperparameters to classifiers errors. In [20], SVM-based fault detection technique for islanded microgrids (MGs) has developed. The fault site is discovered using an inter harmonic injection approach. The approach is tested on 9-bus meshed MG, and it is capable of accurately detecting faults with high fault impedances. In [21], a novel data-driven approach for fault classification has been developed and identified the problem at hierarchical levels in a distribution system. Feeders are monitored through the sensors; smart meters are with sound classifiers. The classifier ML algorithms are ANN (Artificial neural network), SVM (support vector machines) BT and Adaptive Boosting (AdaBoost). A 13-bus test system is taken for the case study and developed method is used for the LG-type fault analysis. The developed strategy is evaluated for their performance under system uncertainties such as incomplete information of observable state measurements and different DG penetration levels. A K-means clustering algorithm is used for prediction of missing data, which improved the overall accuracy.

In [22], authors developed an intelligent strategy for HIF identification that combines Extended Kalman Filter (EKF) and SVM. The suggested technique was trained on 300 datasets and evaluated on 200 datasets, demonstrated its speed, accuracy, and robustness for detecting HIF in distribution feeders. In [23], developed an SVM-based single-pole-to-ground fault location method for MMC-HVDC transmission lines. To achieve an accurate location for various grounding resistance values, the developed location method requires a single ended fault voltage waveform recorded at a fault recording frequency of 20KHZ. In [24], ML algorithm is used for the prediction of HIF on a distribution network. The location identification is done using SVM, NN and LSTM with LSTM and shown high accuracy in HIF detection.

PROPOSED METHODOLOGY

Linear Regression (LR):

Linear Regression method [25] uses labelled data for learning and correlating data points with best-fitting linear functions and predicted the future data. A data set whose corresponding target value is already known is called labelled data. LR algorithm calculates a linear relationship between the dependent variable and one or more independent features through fitting a linear equation to the data obtained, as shown in Figure 1. Simple Linear Regression has one dependent variable and one independent variable as in equation (1).

$$Y = \theta_0 + \theta_1 X \quad (1)$$

Where, Y represents dependent variable, X represents independent variable, θ_0 represents intercept, θ_1 represents slope

Multiple Linear regression consists of one or more independent variable and one dependent variable.

$$Y = \theta_0 + \theta_1 X_1 + \theta_2 X_2 + \dots + \theta_n X_i \quad (2)$$

Where, Y represents dependent variable, X_1, X_2, \dots, X_i are independent variables θ_0 represents intercept, $\theta_1, \theta_2, \dots, \theta_n$ are slopes.

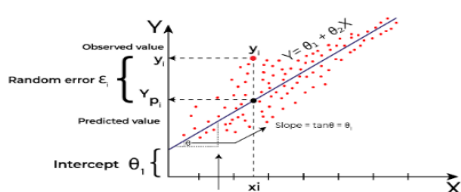


Figure 1: Linear Regression representation

SUPPORT VECTOR MACHINES(SVM):

SVM is a supervised learning technique used for both classification and regression problems [26]. SVM separates n-dimension space that contains different types of data points for classifying new data point into categories. The hyperplane is the specific boundary. SVM selects support vectors and points to draw the hyperplane. support vector concentration technique finds their parametric boundaries that are essential. The figure 2 shows two distinct categories that are categorized using a decision boundary or hyperplane:

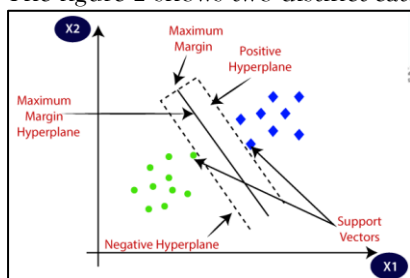


Figure 2: SVM categories

Support vector is the data point or vector, which is closest to the hyperplane and influences its position. These vectors are called support vectors because they support the hyperplane.

More than one line or decision boundary may be required to distinguish classes in an n-dimensional space. The decision boundary is useful in classification of the data points. The dimensions of the hyperplane are based on the dataset features. For two attributes, the hyperplane's dimensions will be a straight line. If hyperplane has two-dimensional plane with three features and maximum distance between data points are included, also known as the maximum margin, when creating a hyperplane.

DESIGN CONSIDERATIONS

IEEE 4-NODE TEST SYSTEM

The single line diagram for the IEEE 4-node test system is shown in the Figure.3.

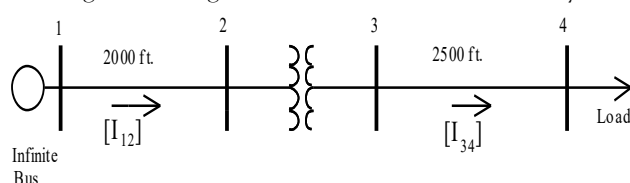


Figure 3: IEEE 4 - node test system

The line and load data of 4 - node test system carry out the short circuit calculations as explained below. The distance between each 4 node has been tabulated as shown in the Table 1.

Table 1: distance between buses for 4-node system

| S. No. | From bus | To bus | Distance in km |
|--------|----------------|--------|----------------|
| 1 | 0 or slack bus | 1 | 0.6096 |
| 2 | 1 | 2 | 0.001 |
| 3 | 2 | 3 | 0.762 |

The resistance and reactance of the lines are tabulated in Table 2.

Table 2: resistance and reactance data for 4-node system

| S. No. | Bus number | R in ohm per km | X in ohm per km | R0 in ohm per km | X0 in ohm per km |
|--------|------------|-----------------|-----------------|------------------|------------------|
| 1 | 0 | 0.1902 | 0.418 | 0.367 | 1.855 |
| 2 | 1 | 0.01 | 0.06 | 0.02 | 0.12 |
| 3 | 2 | 0.1902 | 0.418 | 0.367 | 1.855 |

The load data is stated in table 3.

Table 3: load data for 4-node system

| S. No. | Bus No. | Pa MW | Pb MW | Pc MW | Qa_MVAR | Qb_MVAR | Qc_MVAR |
|--------|---------|-------|-------|-------|---------|---------|---------|
| 1 | 3 | 1275 | 187 | 175 | 0.79 | 0.871 | 0.78 |

IEEE 13 node radial test feeder is used in this study.

The network diagram of 13 node radial test feeder is shown in the Figure 4.

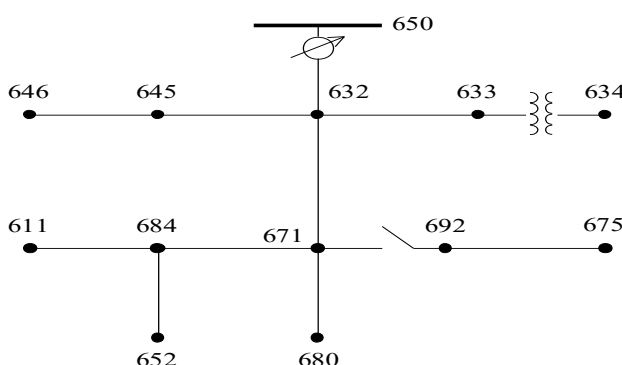


Figure 4: IEEE 13-node test system

For easy computing for the 13-node test system the nodes 650, 632, 633, 634, 645, 646, 671, 692, 675, 684, 911, 652, 680 are written as 0 or slack bus, 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12 respectively. The line data and load data for the IEEE 13- bus test system is tabulated in Table 4 to Table 6.

Table 4: Line data of 13 bus test system

| S. No. | From bus | To bus | Distance in ft | Distance in km |
|--------|-----------|--------|----------------|----------------|
| 1 | Slack bus | 1 | 2000 | 0.6096 |
| 2 | 1 | 2 | 500 | 0.1524 |
| 3 | 2 | 3 | 0 | 0.001 |

| | | | | |
|----|---|----|------|---------|
| 4 | 1 | 4 | 500 | 0.1524 |
| 5 | 4 | 5 | 300 | 0.09144 |
| 6 | 1 | 6 | 2000 | 0.6096 |
| 7 | 6 | 7 | 0 | 0.001 |
| 8 | 7 | 8 | 500 | 0.1524 |
| 9 | 6 | 9 | 300 | 0.09144 |
| 10 | 9 | 10 | 300 | 0.09144 |
| 11 | 9 | 11 | 800 | 0.24384 |
| 12 | 6 | 12 | 1000 | 0.3048 |

Table 5: Resistance and Reactance data between buses

| S. No. | From bus | To bus | R (ohm/km) | X (ohm/km) |
|--------|----------|--------|------------|------------|
| 1 | 0 | 1 | 0.5493 | 1.6649 |
| 2 | 1 | 2 | 1.1964 | 1.9488 |
| 3 | 2 | 3 | 0.011 | 0.02 |
| 4 | 1 | 4 | 2.1299 | 2.1832 |
| 5 | 4 | 5 | 2.1299 | 2.1832 |
| 6 | 1 | 6 | 0.5493 | 1.6649 |
| 7 | 6 | 7 | 0.001 | 0.001 |
| 8 | 7 | 8 | 1.2843 | 0.7181 |
| 9 | 6 | 9 | 2.139 | 2.1675 |
| 10 | 9 | 10 | 2.1387 | 2.1681 |
| 11 | 9 | 11 | 2.1601 | 0.8244 |
| 12 | 6 | 12 | 0.5493 | 1.6649 |

Table 6: Load data for each phase at different buses in test system

| S. No. | Load Bus no. | Phase a | | Phase b | | Phase c | |
|--------|--------------|---------|------------------|---------|------------------|---------|------------------|
| | | MW | MVA _r | MW | MVA _r | MW | MVA _r |
| 1 | 1 | 0.01648 | 0.00945 | 0.06645 | 0.03806 | 0.11697 | 0.06705 |
| 2 | 3 | 0.04263 | 0.02018 | 0 | 0 | 0 | 0 |
| 3 | 4 | 0 | 0 | 0.17053 | 0.12509 | 0 | 0 |
| 4 | 5 | 0 | 0 | 0.23022 | 0.13197 | 0 | 0 |
| 5 | 6 | 0.38370 | 0.21995 | 0.38370 | 0.21995 | 0.38370 | 0.21995 |
| 6 | 7 | 0 | 0 | 0 | 0 | 0.17053 | 0.15138 |
| 7 | 8 | 0.48602 | 0.18907 | 0.06821 | 0.06055 | 0.28991 | 0.21265 |
| 8 | 10 | 0 | 0 | 0 | 0 | 0.17053 | 0.08074 |
| 9 | 11 | 0.12790 | 0.08579 | 0 | 0 | 0 | 0 |

Steps involved in short circuit analysis and ML implementation:

Step 1: Initialize the model:

Firstly, calling the required functions and designing the system model in Jupyter Notebook is done in this phase.

Step 2: Calculating SC currents:

By executing the design model, the SC currents are obtained as Ikss in Kilo Amperes (KA). The values are saved in .csv format excel file for easy computation.

Step 3: training and testing the model:

In this step, the obtained data is split into train and test data for training the model. The predictions of the fault bus are carried out. All the results are saved in both .csv and .png files for validation.

System requirements:

The minimal requirements are to have a system which can run python and scikit learn libraries and matplotlib functions.

RESULTS AND DISCUSSION

For 4-node test system:

The short circuit calculations have been carried out on pandapower [27,28] and the SC current (Ikss) in KA for different values of resistances as per IEC 60909 standards are tabulated for both min and max conditions in Table 7 and Table 8 for 4-node test system.

Table 7: short circuit result max fault condition for 4-node system

| S. No. | Bus number | Ikss (KA) for 5 ohm | Ikss (KA) for 10 ohm | Ikss (KA) for 15 ohm | Ikss (KA) for 20 ohm |
|--------|------------|---------------------|----------------------|----------------------|----------------------|
| 1 | 0 | 1.563468 | 0.786872 | 0.525714 | 0.39471 |
| 2 | 1 | 1.50589 | 0.773552 | 0.519975 | 0.391534 |
| 3 | 2 | 1.505883 | 0.773551 | 0.519975 | 0.391534 |
| 4 | 3 | 1.420943 | 0.754692 | 0.512086 | 0.387251 |

Table 8: short circuit result min fault condition for 4-node system

| S. No. | Bus number | Ikss (KA) for 5 ohm | Ikss (KA) for 10 ohm | Ikss (KA) for 15 ohm | Ikss (KA) for 20 ohm |
|--------|------------|---------------------|----------------------|----------------------|----------------------|
| 1 | 0 | 1.378731 | 0.708188 | 0.47531 | 0.357521 |
| 2 | 1 | 1.300513 | 0.691014 | 0.468197 | 0.353684 |
| 3 | 2 | 1.300504 | 0.691012 | 0.468197 | 0.353683 |
| 4 | 3 | 1.203192 | 0.668495 | 0.458866 | 0.348674 |

The obtained metrics are tabulated in table 9.

Table 9: evaluation metrics for training and testing cases

| S. No. | Evaluation metrics | For Training Dataset | | For Testing Dataset | |
|--------|--------------------|----------------------|--------|---------------------|--------|
| | | LR | SVM | LR | SVM |
| 1. | MAE | 0.3006 | 0.2939 | 0.3332 | 0.2313 |
| 2. | MSE | 0.1354 | 0.1424 | 0.1446 | 0.1193 |
| 3. | R2_score | 0.8862 | 0.8803 | 0.8734 | 0.8955 |

Few values of actual fault bus number and the predicted fault bus number for training and testing cases for IEEE 4-node test system individually for both LR and SVM methods are tabulated in table 10,11,12, and 13 respectively.

Table 10: LR train values and their predicted values

| S. No. | Actual value | Predicted value | S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|--------|--------------|-----------------|
| 1 | 2 | 1.487517 | 14 | 3 | 2.9346 |
| 2 | 3 | 3.064344 | 15 | 1 | 1.459887 |
| 3 | 2 | 1.48848 | 16 | 2 | 1.511997 |
| 4 | 2 | 1.500594 | 17 | 1 | 1.50048 |
| 5 | 2 | 1.460005 | 18 | 0 | 0.088601 |
| 6 | 3 | 3.084425 | 19 | 3 | 3.114139 |
| 7 | 0 | 0.187936 | 20 | 2 | 1.485897 |
| 8 | 0 | 0.051493 | 21 | 3 | 3.115338 |
| 9 | 1 | 1.488362 | 22 | 1 | 1.487403 |
| 10 | 2 | 1.37243 | 23 | 3 | 3.072602 |
| 11 | 3 | 3.023319 | 24 | 0 | 0.000118 |
| 12 | 1 | 1.351785 | 25 | 1 | 1.485779 |
| 13 | 0 | 0.182468 | | | |

Table 11: LR test values and their predicted values

| S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|
| 1 | 1 | 1.372309 |
| 2 | 0 | 0.23982 |
| 3 | 3 | 3.047087 |
| 4 | 0 | 0.263565 |
| 5 | 2 | 1.3519 |
| 6 | 1 | 1.511884 |

| | | |
|---|---|----------|
| 7 | 0 | 0.249988 |
|---|---|----------|

Table 12: SVM train values and their predicted values

| S. No. | Actual value | Predicted value | S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|--------|--------------|-----------------|
| 1 | 2 | 1.356032 | 14 | 3 | 2.928393 |
| 2 | 3 | 3.046317 | 15 | 1 | 1.396755 |
| 3 | 2 | 1.430048 | 16 | 2 | 1.385371 |
| 4 | 2 | 1.380446 | 17 | 1 | 1.380306 |
| 5 | 2 | 1.396895 | 18 | 0 | -0.10005 |
| 6 | 3 | 3.058818 | 19 | 3 | 3.093154 |
| 7 | 0 | 0.09952 | 20 | 2 | 1.433546 |
| 8 | 0 | -0.01884 | 21 | 3 | 3.100263 |
| 9 | 1 | 1.429909 | 22 | 1 | 1.355892 |
| 10 | 2 | 1.331163 | 23 | 3 | 3.048238 |
| 11 | 3 | 3.01836 | 24 | 0 | 0.067202 |
| 12 | 1 | 1.244286 | 25 | 1 | 1.433406 |
| 13 | 0 | 0.100263 | | | |

Table 13: SVM test values and their predicted values

| S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|
| 1 | 1 | 1.331022 |
| 2 | 0 | 0.026457 |
| 3 | 3 | 3.017911 |
| 4 | 0 | 0.055094 |
| 5 | 2 | 1.244427 |
| 6 | 1 | 1.385232 |
| 7 | 0 | 0.048093 |

The actual and predicted fault bus number for both methods is represented graphically as shown in figure 5 and 6.

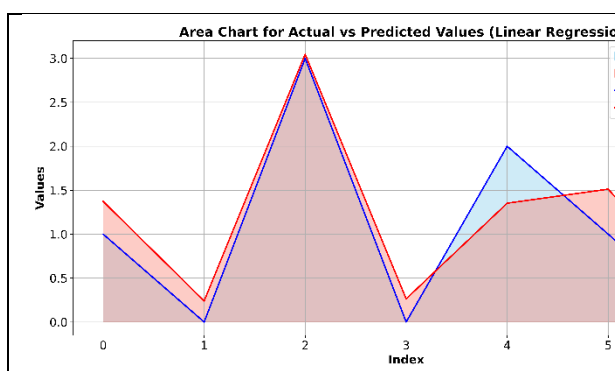


Figure 5: actual vs predicted for linear regression area chart for 4 node test system

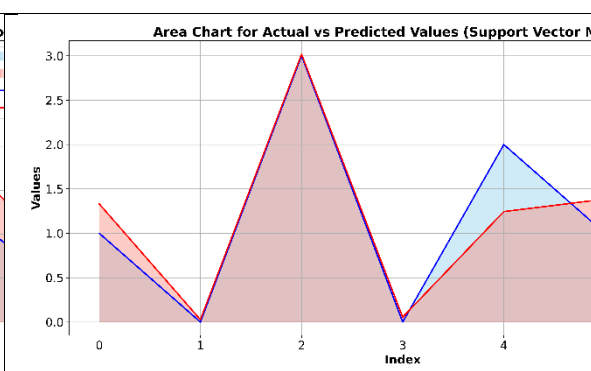


Figure 6: actual vs predicted for support vector machines area chart for 4 node test system

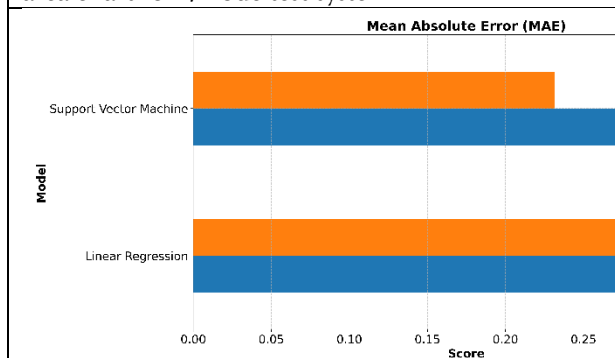


Figure 7: MAE Train vs Test for 4 node test system

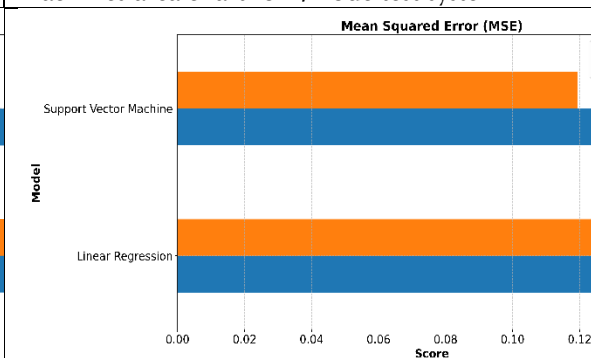


Figure 8: MSE Train vs Test for 4 node test system

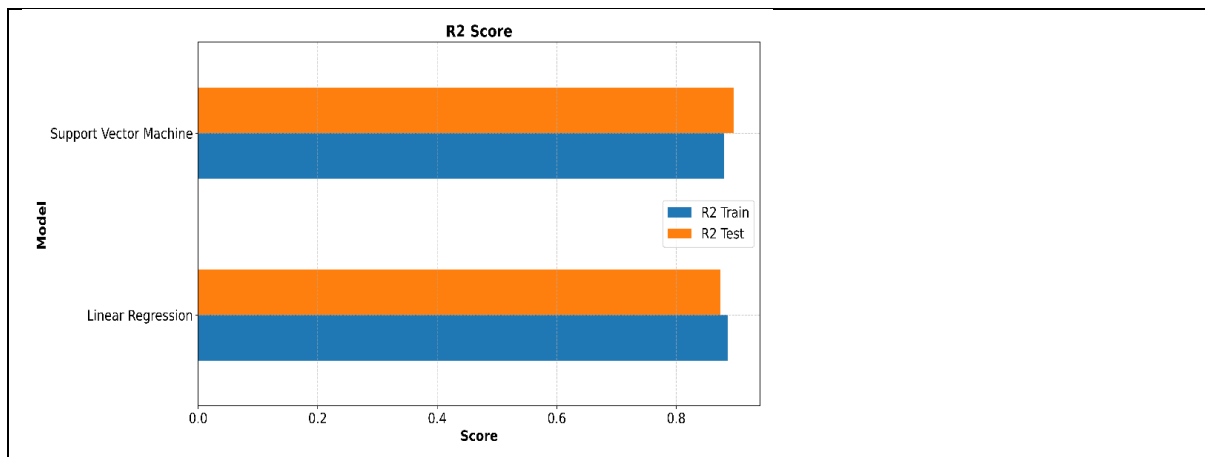


Figure 9: R2 score Train vs Test for 4 node test system

The metrics result plots for MAE, MSE and R2_score for 4-node test system is seen in figure 7,8 and 9 for training and testing the model.

For IEEE 13 bus test system:

Similarly, the same analysis is carried out for IEEE 13 node test system also. The SC results are tabulated in table 14 and 15 for both min and max fault conditions.

Table 14: short circuit result for max fault condition and different ground impedances for IEEE 13-node test system

| S. No. | Bus number | Ikss (KA) for 5 ohm | Ikss (KA) for 10 ohm | Ikss (KA) for 15 ohm | Ikss (KA) for 20 ohm |
|--------|------------|---------------------|----------------------|----------------------|----------------------|
| 1 | 0 | 1.383196 | 0.695112 | 0.464184 | 0.348428 |
| 2 | 1 | 1.229788 | 0.659543 | 0.448966 | 0.340055 |
| 3 | 2 | 1.159602 | 0.641367 | 0.440958 | 0.335592 |
| 4 | 3 | 1.159602 | 0.641367 | 0.440958 | 0.335592 |
| 5 | 4 | 1.123243 | 0.6301 | 0.435632 | 0.332511 |
| 6 | 5 | 1.066632 | 0.613349 | 0.427885 | 0.328086 |
| 7 | 6 | 1.064429 | 0.61887 | 0.431779 | 0.330748 |
| 8 | 7 | 1.064429 | 0.61887 | 0.431779 | 0.330748 |
| 9 | 8 | 1.018197 | 0.603426 | 0.424377 | 0.326453 |
| 10 | 9 | 1.010667 | 0.601854 | 0.423832 | 0.326205 |
| 11 | 10 | 0.961792 | 0.585603 | 0.416105 | 0.321751 |
| 12 | 11 | 0.911939 | 0.56541 | 0.405615 | 0.315397 |
| 13 | 12 | 0.988031 | 0.597818 | 0.422715 | 0.325833 |

Table 15: short circuit result for min fault condition and different ground impedances for IEEE 13-node test system

| S. No. | Bus number | Ikss (KA) for 5 ohm hlf | Ikss (KA) for 10 ohm | Ikss (KA) for 15 ohmHIF | Ikss (KA) for 20 ohm |
|--------|------------|-------------------------|----------------------|-------------------------|----------------------|
| 1 | 0 | 1.269681 | 0.634986 | 0.423349 | 0.317521 |
| 2 | 1 | 1.111112 | 0.597453 | 0.40714 | 0.308554 |
| 3 | 2 | 1.040357 | 0.57855 | 0.398698 | 0.303814 |
| 4 | 3 | 1.040356 | 0.578549 | 0.398698 | 0.303814 |
| 5 | 4 | 1.002386 | 0.566572 | 0.392992 | 0.300499 |
| 6 | 5 | 0.945985 | 0.549274 | 0.384864 | 0.295816 |

| | | | | | |
|----|----|----------|----------|----------|----------|
| 7 | 6 | 0.951638 | 0.556635 | 0.389534 | 0.298902 |
| 8 | 7 | 0.951638 | 0.556635 | 0.389534 | 0.298902 |
| 9 | 8 | 0.904848 | 0.540571 | 0.381732 | 0.294339 |
| 10 | 9 | 0.898489 | 0.539213 | 0.381255 | 0.294122 |
| 11 | 10 | 0.850791 | 0.522738 | 0.373266 | 0.289463 |
| 12 | 11 | 0.799364 | 0.501596 | 0.36217 | 0.282698 |
| 13 | 12 | 0.880268 | 0.536086 | 0.380463 | 0.293904 |

The evaluation metrics result is tabulated in table 16 for training and testing datasets.

Table 16: evaluation metrics for training and testing datasets for 13-node test system

| S. No. | Evaluation metrics | For Training Dataset | | For Testing Dataset | |
|--------|--------------------|----------------------|---------|---------------------|---------|
| | | LR | SVM | LR | SVM |
| 1. | MAE | 1.04608 | 1.02808 | 0.93737 | 0.65555 |
| 2. | MSE | 1.72795 | 2.16279 | 1.38780 | 0.7357 |
| 3. | R2_score | 0.87896 | 0.84851 | 0.89243 | 0.9429 |

Few values of actual fault bus number and the predicted fault bus number for training and testing cases for IEEE 13-node test system individually for both LR and SVM methods are tabulated in table 17,18,19, and 20 respectively.

Table 17: LR train values and their predicted values

| S. No. | Actual value | Predicted value | S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|--------|--------------|-----------------|
| 1 | 5 | 5.388028 | 14 | 5 | 5.500816 |
| 2 | 8 | 8.009742 | 15 | 3 | 4.185817 |
| 3 | 10 | 9.877814 | 16 | 7 | 7.284487 |
| 4 | 7 | 7.400074 | 17 | 12 | 9.859625 |
| 5 | 6 | 7.396686 | 18 | 0 | -2.47572 |
| 6 | 1 | 2.450467 | 19 | 12 | 9.807983 |
| 7 | 9 | 8.281916 | 20 | 4 | 4.323301 |
| 8 | 1 | 2.662984 | 21 | 11 | 10.54494 |
| 9 | 0 | -2.49545 | 22 | 8 | 8.127972 |
| 10 | 6 | 7.35107 | 23 | 12 | 9.550667 |
| 11 | 3 | 3.99517 | 24 | 1 | 2.658319 |
| 12 | 1 | 2.600603 | 25 | 10 | 9.756605 |
| 13 | 6 | 7.284487 | | | |

Table 18: LR test values and their predicted values

| S. No. | Actual value of fault bus | Predicted value Bus no | S. No. | Actual value | Predicted value |
|--------|---------------------------|------------------------|--------|--------------|-----------------|
| 1 | 6 | 7.269125 | 14 | 5 | 5.316361 |
| 2 | 8 | 7.886219 | 15 | 10 | 9.481333 |
| 3 | 12 | 9.440644 | 16 | 4 | 4.378633 |
| 4 | 10 | 9.889817 | 17 | 1 | 2.372711 |
| 5 | 2 | 4.185616 | 18 | 5 | 5.316361 |
| 6 | 9 | 8.582058 | 19 | 11 | 10.15113 |
| 7 | 5 | 5.504597 | 20 | 3 | 4.060776 |
| 8 | 2 | 3.995066 | 21 | 1 | 2.701993 |
| 9 | 1 | 2.481133 | 22 | 8 | 7.782989 |

| | | | | | |
|----|----|----------|----|----|----------|
| 10 | 5 | 5.425619 | 23 | 11 | 10.10045 |
| 11 | 10 | 9.481333 | 24 | 3 | 4.176188 |
| 12 | 4 | 4.378633 | 25 | 8 | 8.131647 |
| 13 | 1 | 2.372711 | | | |

Table 19: SVM train values and their predicted values

| S. No. | Actual value | Predicted value | S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|--------|--------------|-----------------|
| 1 | 5 | 5.038316 | 11 | 5 | 4.953925 |
| 2 | 8 | 8.259974 | 12 | 3 | 3.463688 |
| 3 | 10 | 9.936503 | 13 | 7 | 7.581239 |
| 4 | 7 | 7.606514 | 14 | 12 | 10.44234 |
| 5 | 6 | 7.495657 | 15 | 0 | -3.70923 |
| 6 | 1 | 1.769081 | 16 | 12 | 10.44212 |
| 7 | 9 | 8.731627 | 17 | 5 | 4.953925 |
| 8 | 1 | 1.973282 | 18 | 3 | 3.463688 |
| 9 | 0 | -3.95708 | 19 | 7 | 7.581239 |
| 10 | 6 | 7.611618 | 20 | 12 | 10.44234 |

Table 20: SVM test values and their predicted values

| S. No. | Actual value | Predicted value | S. No. | Actual value | Predicted value |
|--------|--------------|-----------------|--------|--------------|-----------------|
| 1 | 6 | 7.596954 | 11 | 10 | 9.906241 |
| 2 | 8 | 8.147374 | 12 | 4 | 3.725824 |
| 3 | 12 | 10.4031 | 13 | 1 | 1.924184 |
| 4 | 10 | 9.856712 | 14 | 5 | 5.029825 |
| 5 | 2 | 3.463677 | 15 | 11 | 10.03705 |
| 6 | 9 | 8.772508 | 16 | 3 | 3.642477 |
| 7 | 5 | 5.065575 | 17 | 1 | 1.948003 |
| 8 | 2 | 3.614059 | 18 | 8 | 8.251057 |
| 9 | 1 | 1.934997 | 19 | 11 | 10.03876 |
| 10 | 5 | 5.042325 | 20 | 3 | 3.652288 |

The actual and predicted fault bus number for both the methods is represented graphically as shown in figure 10 and 11.

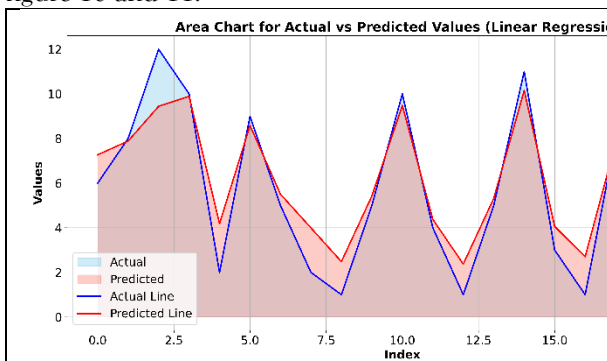


Figure 10: actual vs predicted for linear regression area chart for 13 node test system

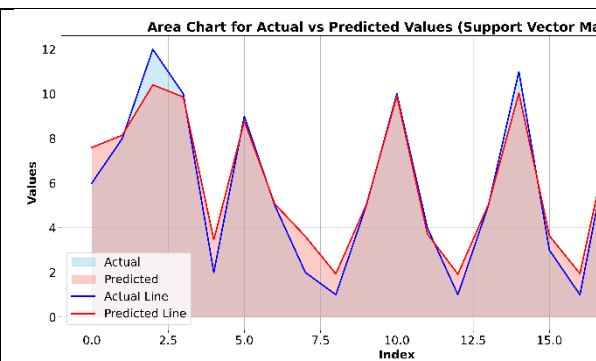


Figure 11: actual vs predicted for support vector machines area chart for 13 node test system

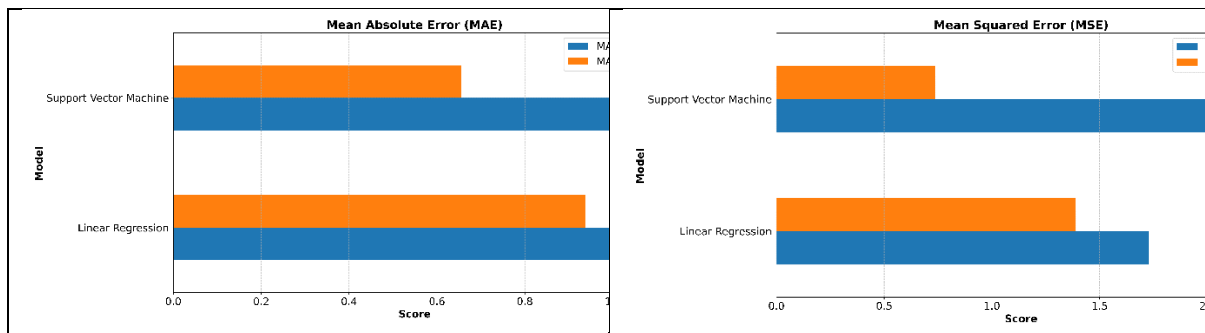


Figure 12: MAE Train vs Test for 13 node test system

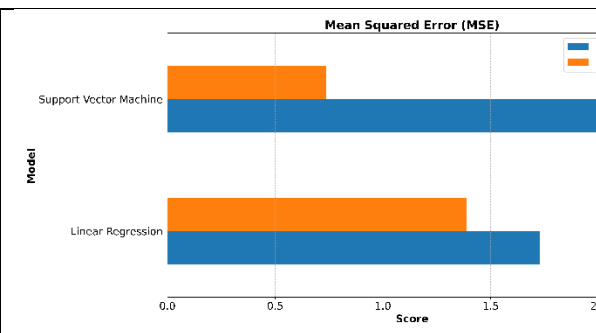


Figure 13: MSE Train vs Test for 13 node test system

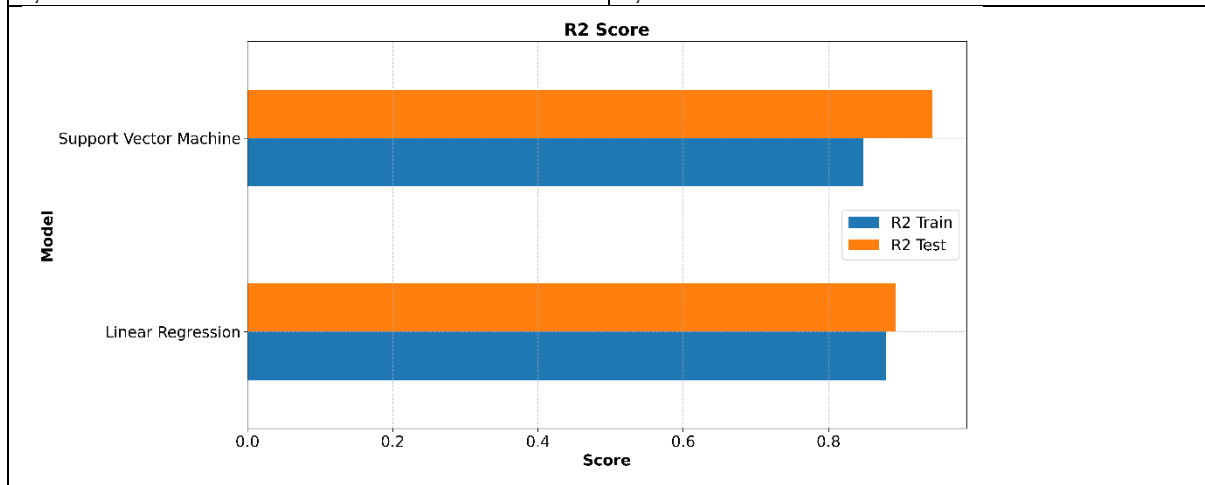


Figure 14: R2 Score Train vs Test for 13 node test system

The metrics result plots for MAE, MSE and R2_score for 13 -node test system is seen in figure 12,13,14 for training and testing the model.

MICROCLIMATIC BASED IGF AND TGF FAULT PREDICTION USING cubic-SVM, and optimized SVM

Table 21 dataset for IGF AND TGF faults in different microclimatic conditions

| Row | Bus No. | Fault Type | Cycle On (ms) | Cycle Off (ms) | Peak Current (kA) | Fault Resistance (Ω) | Temp. ($^{\circ}\text{C}$) | Humidity (%) | Wind Speed (m/s) |
|-----|---------|------------|---------------|----------------|-------------------|-------------------------------|------------------------------|--------------|------------------|
| 1 | 0 | IGF | 14.36 | 34.47 | 0.39 | 108.3 | 32.8 | 61 | 2.7 |
| 2 | 1 | IGF | 28.77 | 15.58 | 0.65 | 90.7 | 32.8 | 61 | 2.7 |
| 3 | 2 | IGF | 23.3 | 21.69 | 0.32 | 174.31 | 32.8 | 61 | 2.7 |
| 4 | 3 | IGF | 19.97 | 24.65 | 0.94 | 103.51 | 32.8 | 61 | 2.7 |
| 5 | 4 | IGF | 8.9 | 28.24 | 0.48 | 92.14 | 32.8 | 61 | 2.7 |
| 6 | 5 | IGF | 8.9 | 41.41 | 0.76 | 131.4 | 32.8 | 61 | 2.7 |
| 7 | 6 | IGF | 6.45 | 17.99 | 0.52 | 71.14 | 32.8 | 61 | 2.7 |
| 8 | 7 | IGF | 26.65 | 30.57 | 0.66 | 170.33 | 32.8 | 61 | 2.7 |
| 9 | 8 | IGF | 20.03 | 33.7 | 0.68 | 61.18 | 32.8 | 61 | 2.7 |
| 10 | 9 | IGF | 22.7 | 11.86 | 0.43 | 198.03 | 32.8 | 61 | 2.7 |

| | | | | | | | | | |
|----|----|-----|-------|-------|------|-------|------|----|-----|
| 11 | 10 | TGF | 19.85 | 21.34 | 0.68 | 152.1 | 32.8 | 61 | 2.7 |
| 12 | 11 | TGF | 25.22 | 12.45 | 0.82 | 140.2 | 32.8 | 61 | 2.7 |
| 13 | 12 | TGF | 30.13 | 17.28 | 0.75 | 160.8 | 32.8 | 61 | 2.7 |
| 1 | 13 | TGF | 27.89 | 19.77 | 0.85 | 132.5 | 32.8 | 61 | 2.7 |
| 5 | 14 | TGF | 21.5 | 15.98 | 0.72 | 148.7 | 32.8 | 61 | 2.7 |
| 6 | 15 | TGF | 24.44 | 18.66 | 0.79 | 145.3 | 32.8 | 61 | 2.7 |
| 7 | 16 | TGF | 29.12 | 14.78 | 0.83 | 138.6 | 32.8 | 61 | 2.7 |
| 8 | 17 | TGF | 22.98 | 16.22 | 0.77 | 155.4 | 32.8 | 61 | 2.7 |
| 9 | 18 | TGF | 26.71 | 13.87 | 0.81 | 142.9 | 32.8 | 61 | 2.7 |
| 10 | 19 | TGF | 28.34 | 15.45 | 0.84 | 150.6 | 32.8 | 61 | 2.7 |

Table 22 Dataset of Single Line to Ground Faults (SLGF) in different microclimatic condition

| S. No. | Bus No. | ISSS (kA) | Temperature (°C) | Humidity (%) | Wind (m/s) | Speed | Fault Type-Different types of SLGF Faults |
|--------|---------|-----------|------------------|--------------|------------|-------|---|
| 1 | 0 | 1.383196 | 32.8 | 61.5 | 2.7 | | ISSS (5Ω) – SIFs |
| 2 | 1 | 1.227978 | 32.8 | 62.30 | 2.7 | | ISSS (5Ω) – SIFs |
| 3 | 2 | 1.159602 | 32.8 | 61.14 | 2.7 | | ISSS (5Ω) – SIFs |
| 4 | 3 | 1.140000 | 32.8 | 61 | 2.7 | | ISSS (5Ω) – SIFs |
| 5 | 4 | 1.123243 | 32.8 | 61 | 2.7 | | ISSS (5Ω) – SIFs |
| 6 | 5 | 0.695112 | 32.8 | 61 | 2.7 | | ISSS (10Ω) – MIFs |
| 7 | 6 | 0.659543 | 32.8 | 61 | 2.7 | | ISSS (10Ω) – MIFs |
| 8 | 7 | 0.641367 | 32.8 | 61 | 2.7 | | ISSS (10Ω) – MIFs |
| 9 | 8 | 0.461484 | 32.8 | 61 | 2.7 | | ISSS (15Ω) – HIFs |
| 10 | 9 | 0.448966 | 32.8 | 61 | 2.7 | | ISSS (15Ω) – HIFs |
| 11 | 10 | 0.348428 | 32.8 | 61 | 2.7 | | ISSS (20Ω) – AGFs/HIFs |
| 12 | 11 | 0.330055 | 32.8 | 61 | 2.7 | | ISSS (20Ω) – AGFs/HIFs |
| 13 | 12 | 0.335892 | 32.8 | 61 | 2.7 | | ISSS (20Ω) – AGFs/HIFs |

(i) CUBIC-SVM

A cubic Support Vector Machine (SVM) is a classification model that uses a third-degree polynomial kernel to separate data that cannot be divided by a straight line. Unlike a linear SVM, which only considers simple boundaries, a cubic SVM maps the input features into a higher-dimensional space where relationships up to the third order are taken into account. This allows the model to capture more complex interactions, such as combinations of variables influencing the output together. The cubic kernel function is expressed as $K(x, x') = (\gamma x^T x' + r)^3$, where γ adjusts the influence of each feature and r is an offset. By raising the inner product to the power of three, the model introduces flexibility while still avoiding the extreme complexity of higher-degree polynomials. In practice, cubic SVMs are often applied to datasets where moderate nonlinear patterns exist, and they generally perform better than linear models when such relationships are present. However, they also require careful tuning of hyperparameters like C , γ , and r , since poor choices can lead to overfitting or underfitting.

(ii) PSO-SVM

PSO-SVM provides highest classification accuracy or lowest validation error. In PSO-SVM, each particle in the swarm represents set of SVM hyperparameters, such as C and γ . The position of a particle is a vector $[C, \gamma]$. The fitness of a particle is evaluated by training an SVM with those parameters on training data and measuring its performance on validation data. The swarm iteratively updates particle positions and velocities to find better solutions over generations. This process continues until convergence criteria are met. Manual tuning is labor-intensive and often suboptimal, especially when the parameter

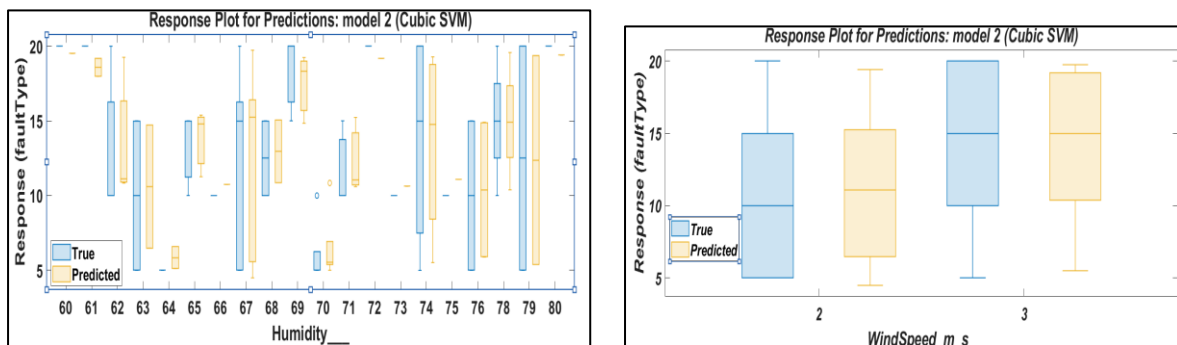
space is large or contains complex interactions. PSO automates through trial-and-error approaches and ensures more systematic search for optimal parameters.

(iii) BO-SVM

Bayesian Optimization selects SVM hyperparameters and increases the predictive accuracy. BO-SVM performs efficient evaluations and handles noisy objective measurements. BO-SVM avoids local minima and scalable for higher dimensional hyperparameter spaces. BO-SVM Controls trade-off between margin maximization and classification error through C , which is a regularization parameter and Controls how far the influence of a single training point reaches through γ (gamma in RBF kernel). These tuning avoids underfitting or overfitting. BO-SVM find the values of hyperparameters such as C , γ , that minimizes an error metric. For the prediction of the faults in the IGF and TGF, the proposed algorithms such as (i) Cubic-SVM (ii) PSO-SVM (iii) BO-SVM are applied.

COMPARISON OF CUBIC-SVM, PSO-SVM, AND BO-SVM IN FAULT PREDICTION FOR IGF AND TGF SYSTEMS

For predicting the type of faults such as IGF and TGF, Cubic-SVM, PSO-SVM, and BO-SVM algorithms are used and evaluated the key metrics such as precision, accuracy, and recall for assessment of their effectiveness. The Cubic-SVM method has robust decision boundaries, demonstrated reliable accuracy and balanced recall. However, Particle Swarm Optimization (PSO) and Bayesian Optimization (BO) are integrated with SVM, and provides higher precision and recall, minimizing false alarms and missed detections in fault prediction scenarios. BO-SVM method has achieved the highest accuracy and maintains strong precision and recall. Cubic-SVM provides high accuracy in fault detection. Cubic_SVM leads to more reliable and accurate fault detection such as IGF and TGF and supports for the maintenance decisions and system reliability.



(a) Humidity (b) WindSpeed

Figure 15 Cubic-SVM based fault type and (a) Humidity relation, (b) Windspeed.

Cubic-SVM achieves balanced accuracy and recall, and detects initial fault detection tasks. Cubic-SVM performance may plateau without further optimization, especially in complex or noisy datasets. PSO-SVM fine-tunes SVM parameters dynamically and provides higher precision and recall, which reduces both false positives and false negatives in fault prediction. PSO-SVM minimizes missed detections and false alarms. PSO enhances the SVM's adaptability to data patterns. BO-SVM uses probabilistic modeling to optimize SVM hyperparameters efficiently. BO-SVM leads to the highest accuracy and maintains strong precision and recall. The systematic search for optimal parameters ensures robust performance, even as data characteristics shift or become more complex. Cubic-SVM provides a solid starting point with reliable, balanced results. PSO-SVM enhances detection by adaptively tuning model parameters, leading to better fault identification and fewer errors. Cubic-SVM is effective, significantly boosts predictive accuracy and reliability for fault detection in IGF and TGF systems. This leads to more informed maintenance and operational decisions, ultimately improving system reliability and safety.

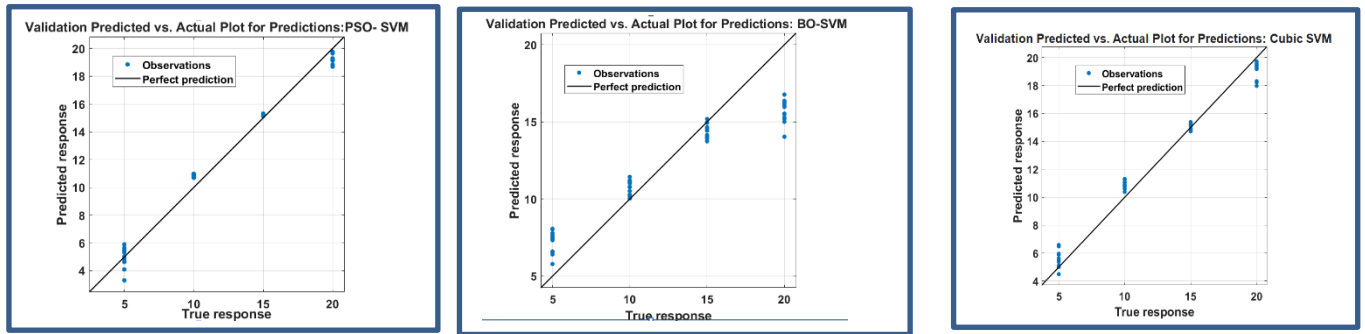


Figure 16 Cubic-SVM, PSO-SVM and BO-SVM Fault type prediction response in different types of microclimatic conditions.

Table 23 shows the IGF and TGF fault detection in different microclimatic condition. Table 24 shows Single Line to Ground Faults (SLGF) in different microclimatic condition.

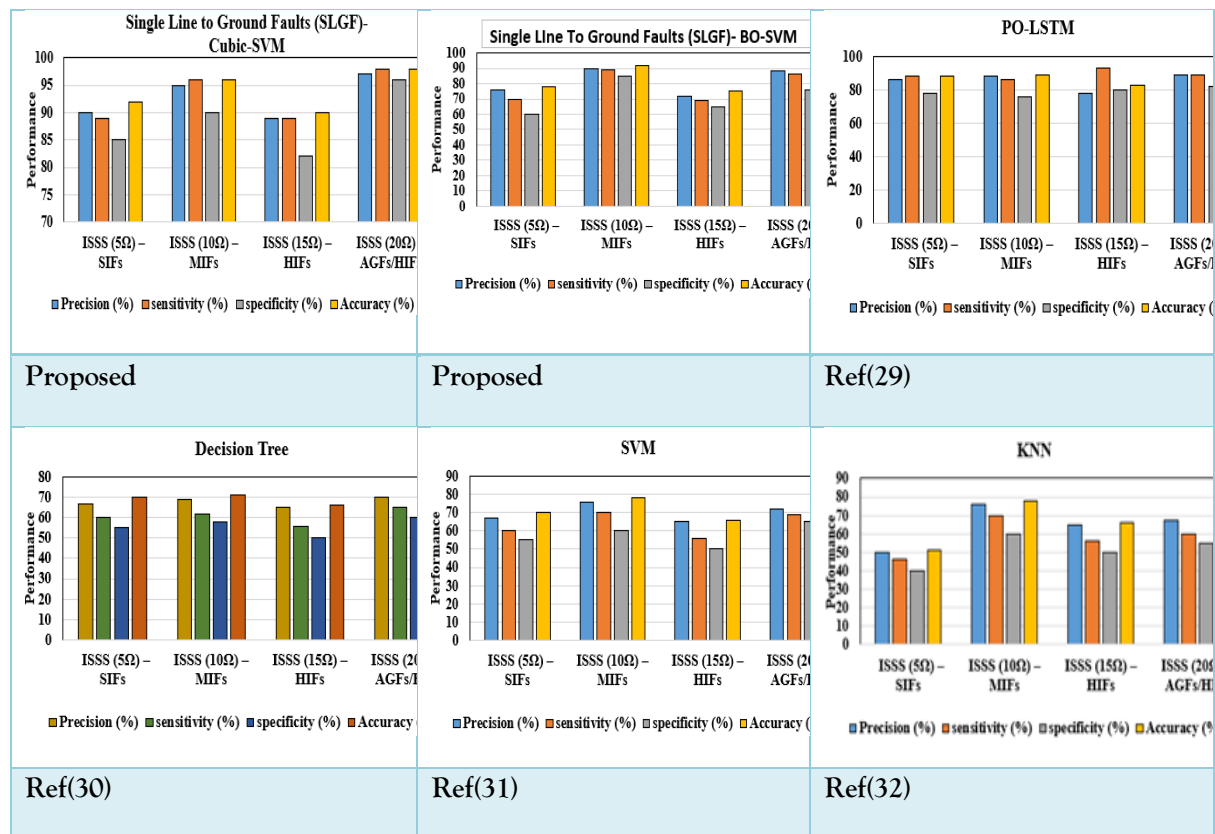


Table 23 IGF and TGF fault detection in different microclimatic condition

| Algorithm | Precision (%) | Accuracy (%) | Recall (%) | Key Advantage in |
|-----------|---------------|--------------|------------|---|
| Cubic-SVM | 95 | 97 | 96 | Efficient optimization, best overall accuracy |
| PSO-SVM | 82 | 87 | 89 | Adaptive parameter tuning, fewer false alarms |

| | | | | | |
|---------------|----|----|----|--------------------|----------|
| BO-SVM | 85 | 90 | 93 | Robust performance | baseline |
|---------------|----|----|----|--------------------|----------|

Table 24 Single Line to Ground Faults (SLGF) in different microclimatic condition

| Algorithm | Precision (%) | Accuracy (%) | Recall (%) | Key Advantage in Single Line to Ground Faults (SLGF) detection | |
|------------------|---------------|--------------|------------|--|----------|
| Cubic-SVM | 96 | 98 | 97 | Efficient optimization, best overall accuracy | |
| PSO-SVM | 84 | 83 | 86 | Adaptive parameter tuning, fewer false alarms | |
| BO-SVM | 95 | 92 | 94 | Robust performance | baseline |

CONCLUSION

From the analysis, the Cubic-SVM and BO-SVM algorithm attained better results when compared to linear regression model. The cubic-SVM evaluation metric values of MAE of 0.2313, 0.65555 and MSE of 0.1193, 0.7357 and R2_score of 0.8955, 0.9429 when compared to that of LR method with MAE of 0.3332, 0.65555 and MSE of 0.1446, 0.7357 and R2_score of 0.8734, 0.9429 are obtained for IEEE 4-node and 13 - node radial test systems for detecting the HIF accurately. The cubic-SVM method has been suggested as best trained model with less error. Table 24 shows the overall performance of the proposed algorithm such as Single Line to Ground Faults (SLGF) IGF and TGF fault in different microclimatic condition and without including the microclimatic data in the algorithm.

Table 25. Comparison of proposed algorithm with and without microclimatic data for SLGF types and IGF and TGF fault predictions

| Single Line to Ground Faults (SLGF) in different microclimatic condition | | | |
|--|-----------|----------|--------|
| Algorithm | Precision | Accuracy | Recall |
| Without Microclimatic Data | | | |
| Cubic-SVM | 90 | 92 | 91 |
| BO-SVM | 80 | 91 | 90 |
| With Microclimatic Data | | | |
| Cubic-SVM | 95 | 97 | 96 |
| BO-SVM | 85 | 90 | 93 |
| IGF and TGF fault detection in different microclimatic condition | | | |
| Algorithm | Precision | Accuracy | Recall |
| Without Microclimatic Data | | | |
| Cubic-SVM | 90 | 92 | 91 |
| BO-SVM | 80 | 91 | 90 |
| With Microclimatic Data | | | |
| Cubic-SVM | 95 | 97 | 96 |
| BO-SVM | 85 | 90 | 93 |

In future, the implementation of combination of such ML techniques may give better metrics when compared with other conventional methods.

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